

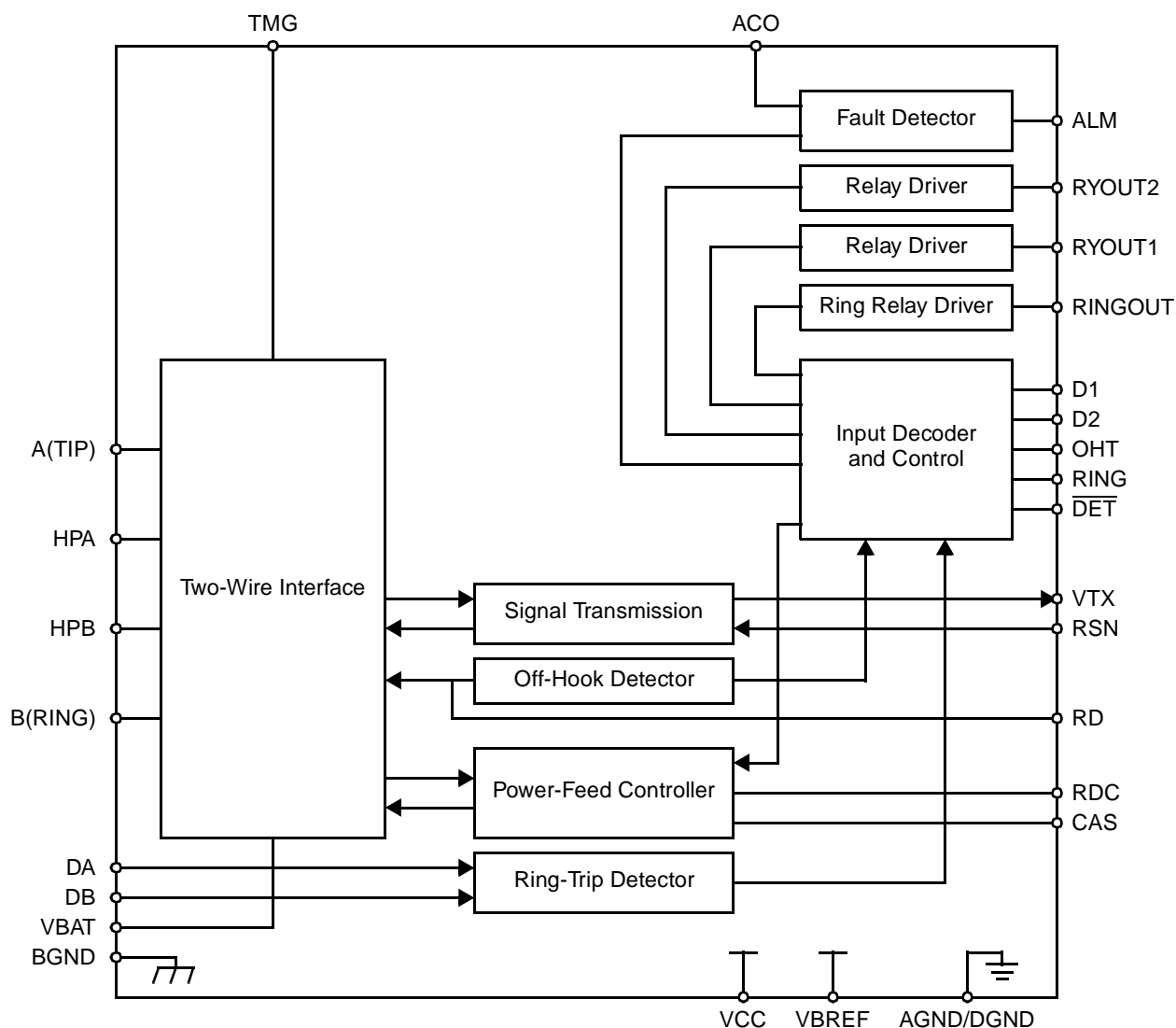
# Am7924

## Subscriber Line Interface Circuit

### DISTINCTIVE CHARACTERISTICS

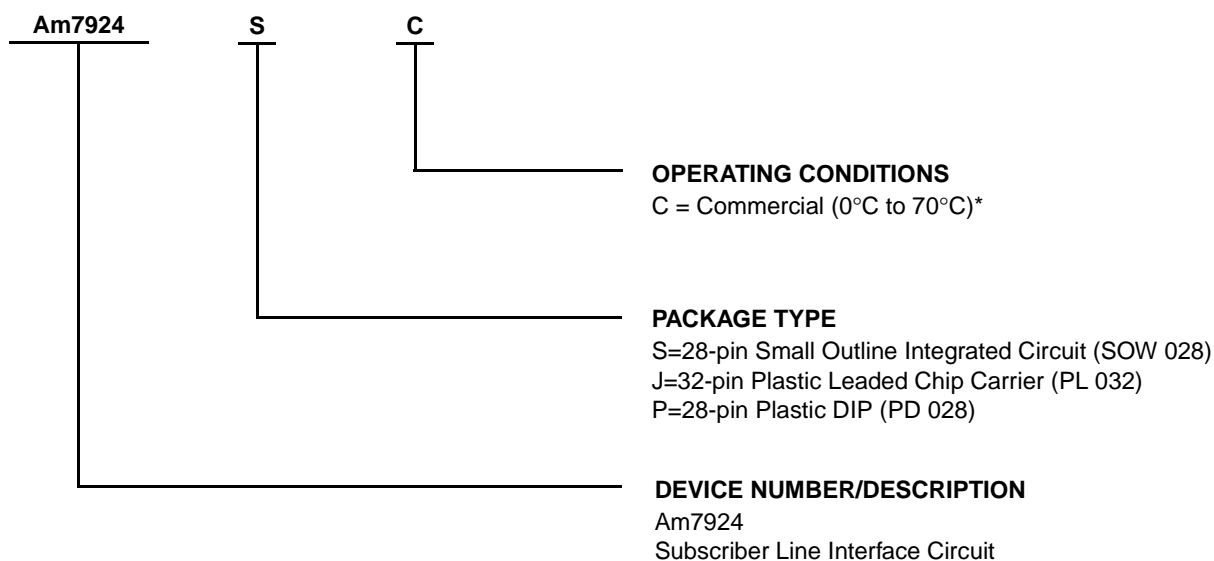
- Control states: Active and Ringing
- -19 V to -58 V battery operation
- On-hook transmission
- Two-wire impedance set by single external impedance
- No -5 V supply required
- Fault detectors
- Programmable constant-current feed
- Programmable loop-detect threshold
- Programmable ring-trip detect threshold
- Current gain = 500
- On-chip Thermal Management (TMG) feature
- Three on-chip relay drivers and relay snubbers, one ringing and two general purpose

### BLOCK DIAGRAM



**ORDERING INFORMATION****Standard Products**

AMD standard products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of the elements below.



Valid Combinations	
Am7924	SC JC PC

**Valid Combinations**

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations, to check on newly released combinations, and to obtain additional data on AMD's standard military grade products.

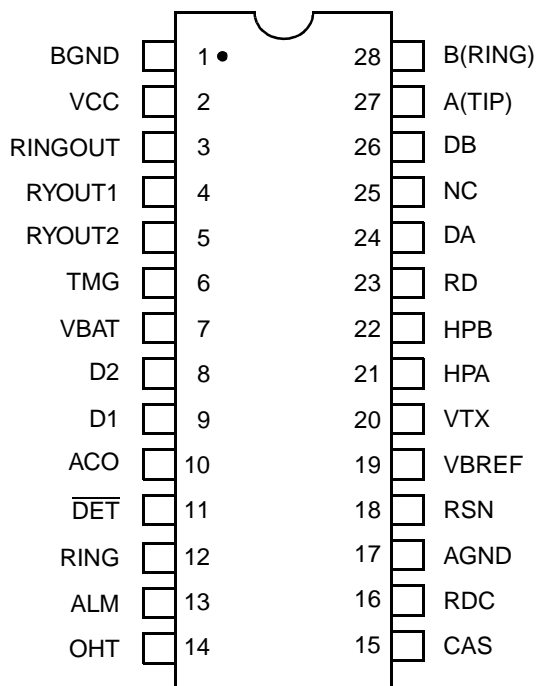
**Note:**

\* Functionality of the device from 0°C to +70°C is guaranteed by production testing. Performance from -40°C to +85°C is guaranteed by characterization and periodic sampling of production units.

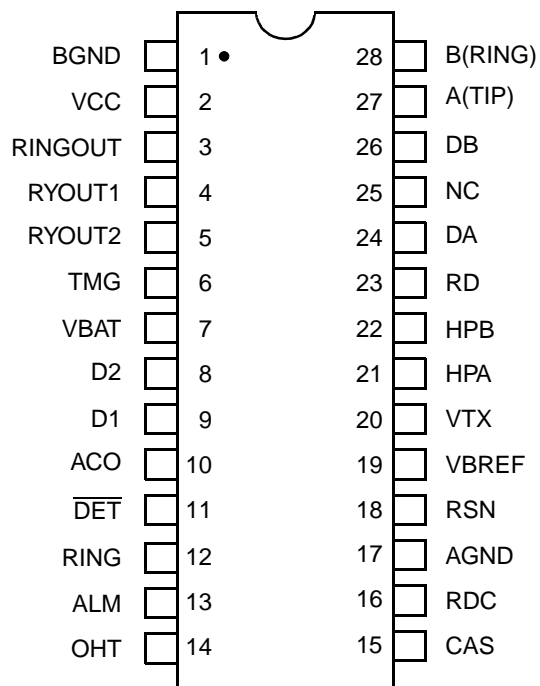
## CONNECTION DIAGRAMS

## Top View

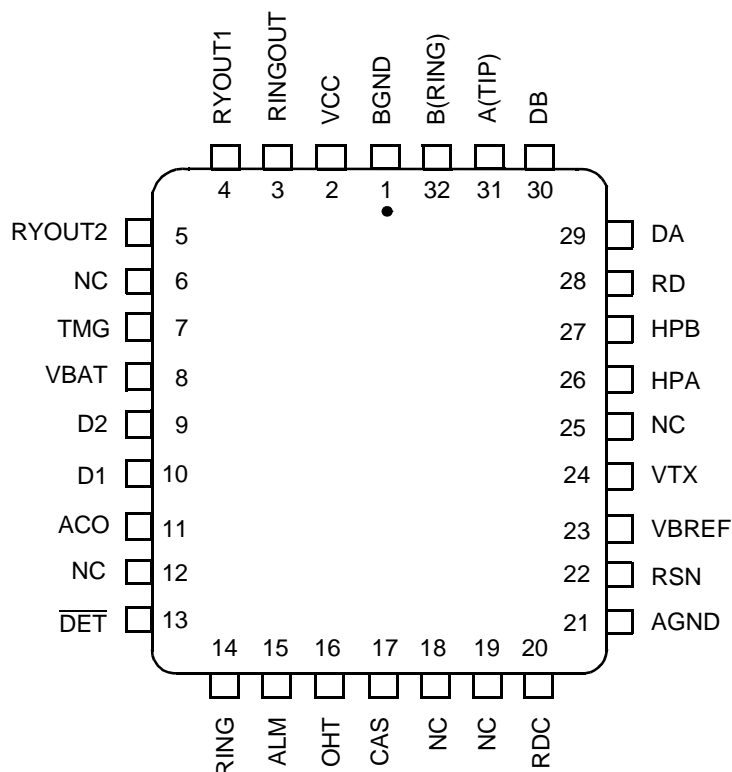
28-Pin SOIC



28-Pin DIP



32-Pin PLCC

**Notes:**

1. Pin 1 is marked for orientation.
2. NC = No connect

## PIN DESCRIPTIONS

Pin Names	Type	Description
ACO	Input	Overvoltage Alarm. Input from external resistor allows detection of positive overvoltages on the line. Detection forces ALM and $\overline{\text{DET}}$ Low.
AGND/DGND	Gnd	Analog and Digital ground.
A(TIP)	Output	Output of A(TIP) power amplifier.
BGND	Gnd	Battery (power) ground.
B(RING)	Output	Output of B(RING) power amplifier.
CAS	Capacitor	Anti-saturation pin for capacitor to filter reference voltage when operating in anti-saturation region.
D2–D1	Input	D1 and D2 control the relay drivers RYOUT1 and RYOUT2. A logic High on D1 activates the RYOUT1 relay driver. A logic High on D2 activates the RYOUT2 relay driver. TTL compatible.
DA	Input	Ring-trip negative. Negative input to ring-trip comparator.
DB	Input	Ring-trip positive. Positive input to ring-trip comparator.
$\overline{\text{DET}}$	Output	Detector. Logic Low indicates that the selected detector is tripped. Logic inputs C2 and C1 select the detector. Open-collector with a built-in 15 k $\Omega$ pull-up resistor.
HPA	Capacitor	High-Pass Filter Capacitor. A(TIP) side of high-pass filter capacitor.
HPB	Capacitor	High-Pass Filter Capacitor. B(RING) side of high-pass filter capacitor.
NC	—	No connect. Pin not internally connected.
OHT	Input	On-hook transmission. A logic High sets the SLIC in the Active state. A logic Low sets the SLIC in the On-Hook Transmission (OHT) state.
RD	Resistor	Detector resistor. Detector threshold set and filter pin.
RDC	Resistor	DC feed resistor. Connection point for the DC feed current programming network. The other end of the network connects to the receiver summing node (RSN).
RING	Input	SLIC control pin. TTL compatible. A logic High on RING forces the device into the Ringing state. A logic Low puts the SLIC into the Active state.
RINGOUT	Output	Ring Signal Driver. Open-collector driver with emitter internally connected to BGND.
RSN	Input	The metallic current (AC and DC) between A(TIP) and B(RING) is equal to 500 x the current into this pin. The networks that program receive gain, two-wire impedance, and feed current all connect to this node.
RYOUT1, RYOUT2	Output	Relay/Switch Driver. Open-collector driver with emitter internally connected to BGND.
TMG	—	Thermal Management. External resistor connects between this pin and VBAT to offload power from SLIC.
VBAT	Battery	Battery supply and connection to substrate.
VBREF	—	This is an AMD-reserved pin and must always be connected to the VBAT pin.
VCC	Power	+5 V power supply.
VTX	Output	Transmit Audio. This output is a unity gain version of the A(TIP) and B(RING) metallic voltage. VTX also sources the two-wire input impedance programming network.

**ABSOLUTE MAXIMUM RATINGS**

Storage temperature	−55°C to +150°C
V <sub>CC</sub> with respect to AGND/DGND	−0.4 V to +7.0 V
V <sub>BAT</sub> with respect to AGND/DGND:	
Continuous	+0.4 V to −70 V
10 ms.	+0.4 V to −75 V
BGND with respect to AGND/DGND	+3 V to −3 V
A(TIP) or B(RING) to BGND:	
Continuous	V <sub>BAT</sub> to +1 V
10 ms (f = 0.1 Hz)	−70 V to +5 V
1 μs (f = 0.1 Hz)	−80 V to +8 V
250 ns (f = 0.1 Hz)	−90 V to +12 V
Current from A(TIP) or B(RING)	±150 mA
RINGOUT, RYOUT1, and RYOUT2 outputs:	
Current	90 mA
Voltage	BGND to +7 V
Transient	BGND to +10 V
DA and DB inputs:	
Voltage on ring-trip inputs	V <sub>BAT</sub> to 0 V
Current into ring-trip inputs	±10 mA
OHT, RING, D2–D1, and ACO:	
Input voltage	−0.4 V to (V <sub>CC</sub> + 0.4 V)
Maximum power dissipation, continuous, T <sub>A</sub> = 70°C, No heat sink (See note):	
In 28-pin SOIC package	1.1 W
In 32-pin PLCC package	1.5 W
In 28-pin DIP package	1.3 W
Thermal Data:	θ <sub>JA</sub>
In 28-pin SOIC package	60°C/W typ
In 32-pin PLCC package	50°C/W typ
In 28-pin PDIP package	43°C/W typ
ESD immunity/pin (HBM)	1500 V

**Note:** Thermal limiting circuitry on chip will shut down the circuit at a junction temperature of about 165°C. The device should never be exposed to this temperature. Operation above 145°C junction temperature may degrade device reliability. See the SLIC Packaging Considerations for more information.

Stresses above those listed under Absolute Maximum Ratings may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to Absolute Maximum Ratings for extended periods may affect device reliability.

**OPERATING RANGES****Commercial (C) Devices**

Ambient temperature	0°C to +70°C*
V <sub>CC</sub>	4.75 V to 5.25 V
V <sub>BAT</sub>	−19 V to −58 V
AGND/DGND	0 V
BGND with respect to AGND/DGND	−100 mV to +100 mV
Load resistance on VTX to ground	20 kΩ min

*Operating Ranges define those limits between which device functionality is guaranteed.*

*\* Functionality of the device from 0°C to +70°C is guaranteed by production testing. Performance from −40°C to +85°C is guaranteed by characterization and periodic sampling of production units.*

## ELECTRICAL CHARACTERISTICS

Description	Test Conditions (See Note 1)	Min	Typ	Max	Unit	Note
Transmission Performance						
2-wire return loss	200 Hz to 3.4 kHz	26			dB	1, 4
Analog output (V <sub>TX</sub> ) impedance			3	20	Ω	4
Analog (V <sub>TX</sub> ) output offset voltage		−50		+50	mV	
Overload level, 2-wire and 4-wire	Active state	2.5			V <sub>pk</sub>	2a
Overload level	On hook, R <sub>LAC</sub> = 600 Ω	0.77			V <sub>rms</sub>	2b
THD, Total Harmonic Distortion	0 dBm +7 dBm		−64 −55	−50 −40	dB	5
THD, on hook	0 dBm, R <sub>LAC</sub> = 600 Ω			−36		
Longitudinal Capability (See Test Circuit D)						
Longitudinal to metallic, L-T, L-4 balance	200 Hz to 1 kHz 1 kHz to 3.4 kHz	53 53			dB	
Longitudinal signal generation 4-L	200 Hz to 3.4 kHz	40				
Longitudinal current per pin (A or B)	Active state On hook	12.5 12.5	18 18		mArms	8
Longitudinal impedance (A or B)	0 to 100 Hz		25	35	Ω/pin	
Idle Channel Noise						
C-message weighted noise	R <sub>L</sub> = 600 Ω		+7	+12	dBrnC	4
Psophometric weighted noise	R <sub>L</sub> = 600 Ω		−83	−78	dBmp	
Insertion Loss and Balance Return Signal (See Test Circuits A and B)						
Gain accuracy 4- to 2-wire	0 dBm, 1 kHz	−0.20	0	+0.20	dB	4
Gain accuracy 2- to 4-wire, 4- to 4-wire	0 dBm, 1 kHz	−6.22	−6.02	−5.82		
Gain accuracy, 4- to 2-wire	On hook	−0.35		+0.35		
Gain accuracy, 2- to 4-wire, 4- to 4-wire	On hook	−6.37	−6.02	−5.67		
Gain accuracy over frequency	300 Hz to 3400 Hz relative to 1 kHz	−0.15		+0.15		
Gain tracking	+3 dBm to −55 dBm relative to 0 dBm	−0.15		+0.15		
Gain tracking On hook	0 dBm to −37 dBm +3 dBm to 0 dBm	−0.15 −0.35		+0.15 +0.35		
Group delay	0 dBm, 1 kHz		4		μs	4, 7

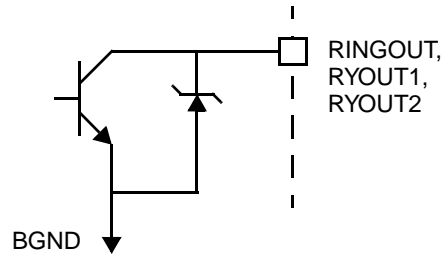
## ELECTRICAL CHARACTERISTICS (CONTINUED)

Description	Test Conditions (See Note 1)	Min	Typ	Max	Unit	Note
Line Characteristics						
I <sub>L</sub> , Short loops, Active or Standby	R <sub>LDC</sub> = 600 Ω	35.5	40	44.5	mA	
I <sub>L</sub> , Long loops, Active	BAT = −48 V, R <sub>LDC</sub> = 1900 Ω	20	21.3			
I <sub>L</sub> LIM	Active, A and B to ground		70	100		
V <sub>AB</sub> , Open circuit voltage	V <sub>BAT</sub> = −48 V, Active state	V <sub>BAT</sub> + 3.0	V <sub>BAT</sub> + 1.5		V	
	OHT = 0	V <sub>BAT</sub> + 8.0	V <sub>BAT</sub> + 6.0			
Power Supply Rejection Ratio (V <sub>RI</sub> PPLE = 100 mVrms), Active Normal State						
V <sub>CC</sub>	50 Hz to 3.4 kHz	30	40		dB	5
V <sub>BAT</sub>	50 Hz to 3.4 kHz	28	50			
Effective internal resistance	CAS pin to V <sub>BAT</sub>	85	170	255	kΩ	4
Power Dissipation						
On hook, Active state	R <sub>TMG</sub> = 1 kΩ		120	180	mW	
Off hook, Active state	R <sub>L</sub> = 300 Ω, R <sub>TMG</sub> = 1 kΩ		1150	1350		
Supply Currents, Battery = −48 V						
I <sub>CC</sub> , on-hook V <sub>CC</sub> supply current	Active state, V <sub>BAT</sub> = −48 V		5.5	8.5	mA	
I <sub>BAT</sub> , on-hook V <sub>BAT</sub> supply current	Active state, V <sub>BAT</sub> = −48 V		2.0	3.4		
RFI Rejection						
RFI rejection	100 kHz to 30 MHz (see Figure E)			1.0	mVrms	4
Receive Summing Node (RSN)						
RSN DC voltage	I <sub>RSN</sub> = 0 mA		0		V	4
RSN impedance	200 Hz to 3.4 kHz		10	20	Ω	
Logic Inputs (OHT, RING, D2–D1)						
V <sub>IH</sub> , Input High voltage		2.0			V	
V <sub>IL</sub> , Input Low voltage				0.8		
I <sub>IH</sub> , Input High current		−75		40	μA	
I <sub>IL</sub> , Input Low current		−400				
Logic Output ( $\overline{\text{DET}}$ , ALM)						
V <sub>OL</sub> , Output Low voltage	I <sub>OUT</sub> = 0.3 mA			0.40	V	
V <sub>OH</sub> , Output High voltage	I <sub>OUT</sub> = −0.1 mA	2.4				
$\overline{\text{DET}}$ pull-up resistor to V <sub>CC</sub>		9.5	15		kΩ	
ALM pull-up resistor to V <sub>CC</sub>		4	6.5			
Ring-Trip Detector Input (DA, DB)						
Bias current		−500	−50		nA	
Offset voltage	Source resistance = 2 MΩ	−50	0	+50	mV	6

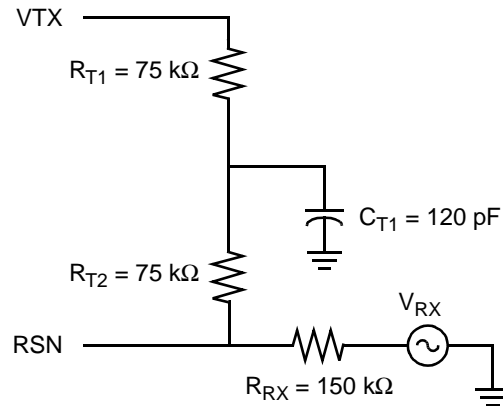
## ELECTRICAL CHARACTERISTICS (CONTINUED)

Description	Test Conditions (See Note 1)	Min	Typ	Max	Unit	Note
<b>Loop Detector</b>						
$R_{LTH}$ , Loop-detect threshold tolerance	$R_D = 35.4\text{ k}\Omega$	3.0	3.54	4.1	$\text{k}\Omega$	
$I_{ACO}$ , ACO fault input detect		220	320	420	$\mu\text{A}$	
<b>Relay Driver Output (RINGOUT, RYOUT1, RYOUT2)</b>						
On voltage	$I_{OL} = 40\text{ mA}$ RINGOUT, RYOUT1, RYOUT2		+0.35	+0.6	V	
On voltage	$I_{OL} = 80\text{ mA}$ , RINGOUT		0.75	1.0		
Off leakage	$V_{OH} = +5\text{ V}$			100	$\mu\text{A}$	
Zener breakover	$I_Z = 100\text{ }\mu\text{A}$	6	7.2		V	
Zener On voltage	$I_Z = 30\text{ mA}$		8			

## RELAY DRIVER SCHEMATIC

**Notes:**

1. Unless otherwise noted, test conditions are  $BAT = -48\text{ V}$ ,  $V_{CC} = +5\text{ V}$ ,  $R_L = 600\text{ }\Omega$ ,  $R_{DC1} = R_{DC2} = 15.625\text{ k}\Omega$ ,  $R_{TMG} = 1\text{ k}\Omega$ ,  $R_D = 35.4\text{ k}\Omega$ , no fuse resistors,  $C_{HP} = 0.22\text{ }\mu\text{F}$ ,  $C_{DC} = 220\text{ nF}$ ,  $C_{CAS} = 0.33\text{ }\mu\text{F}$ ,  $D_1 = 1\text{N400x}$ , two-wire AC input impedance is a  $600\text{ }\Omega$  resistance synthesized by the programming network shown below.



2. a. Overload level is defined when  $THD = 1\%$ .  
b. Overload level is defined when  $THD = 1.5\%$ .
3. Balance return signal is the signal generated at  $V_{TX}$  by  $V_{RX}$ . This specification assumes the two-wire AC load impedance matches the programmed impedance.
4. Not tested in production. This parameter is guaranteed by characterization or correlation to other tests.
5. This parameter is tested at  $1\text{ kHz}$  in production. Performance at other frequencies is guaranteed by characterization.
6. Tested with  $0\text{ }\Omega$  source impedance.  $2\text{ M}\Omega$  is specified for system design only.
7. Group delay can be greatly reduced by using a  $Z_T$  network such as that shown in Note 1 above. The network reduces the group delay to less than  $2\text{ }\mu\text{s}$  and increases  $2\text{WRL}$ . The effect of group delay on linecard performance also may be compensated for by synthesizing complex impedance with the QSLAC™ or DSLAC™ device.
8. Minimum current level guaranteed not to cause a false loop detect.



Table 1. SLIC Decoding

State	Ring	Two-Wire Status	$\overline{\text{DET}}$ Output	Ring Relay
0	0	Active	Loop detector	Off
1	1	Ringing	Ring trip	On

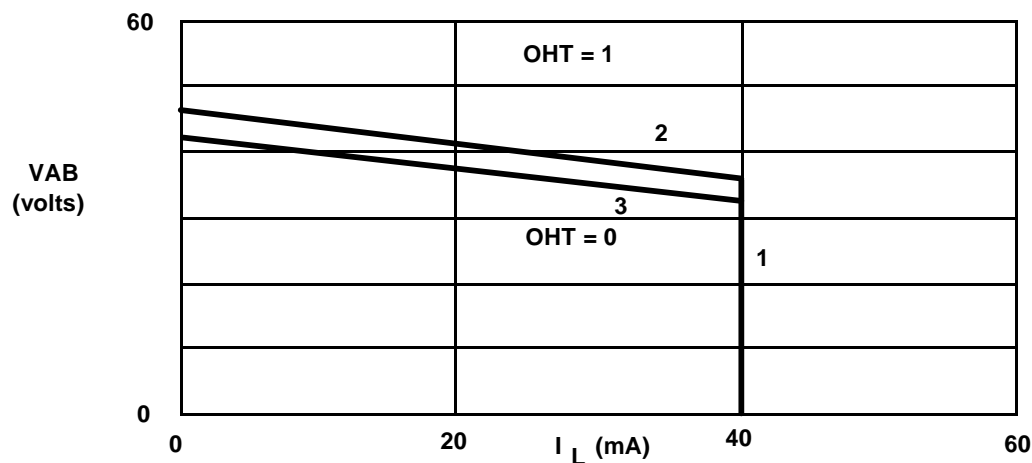
Table 2. SLIC Input/Output

	0	1	Note
$\overline{\text{DET}}$	Off hook or fault	On hook	Output
ALM	Fault	Normal	Input
OHT	OHT state	Active state	Input
D1	RYOUT1 inactive	RYOUT1 active	Input
D2	RYOUT2 inactive	RYOUT2 active	Input

Table 3. User-Programmable Components

$Z_T = 250(Z_{2\text{WIN}} - 2R_F)$	$Z_T$ is connected between the VTX and RSN pins. The fuse resistors are $R_F$ and $Z_{2\text{WIN}}$ is the desired 2-wire AC input impedance. When computing $Z_T$ , the internal current amplifier pole and any external stray capacitance between VTX and RSN must be taken into account.
$Z_{RX} = \frac{Z_L}{G_{42L}} \cdot \frac{500Z_T}{Z_T + 250(Z_L + 2R_F)}$	$Z_{RX}$ is connected from $V_{RX}$ to $R_{SN}$ , $Z_T$ is defined above, and $G_{42L}$ is the desired receive gain.
$R_{DC1} + R_{DC2} = \frac{1250}{I_{\text{LOOP}}}$ $C_{DC} = 1.5 \text{ ms} \cdot \frac{R_{DC1} + R_{DC2}}{R_{DC1}R_{DC2}}$	$R_{DC1}$ , $R_{DC2}$ , and $C_{DC}$ form the network connected to the RDC pin. $R_{DC1}$ and $R_{DC2}$ are approximately equal. $I_{\text{LOOP}}$ is the desired loop current in the constant-current region.
$R_{LTH} = \frac{R_D}{10}$	$R_D$ is the resistor connected from $R_D$ to ground, and $R_{LTH}$ is the loop-resistance threshold between on-hook and off-hook detection.
$C_{CAS} = \frac{1}{3.4 \cdot 10^5 \pi f_c}$	$C_{CAS}$ is the regulator filter capacitor and $f_c$ is the desired filter cut-off frequency.
<b>Thermal Management Equations (Normal Active and Tip Open States)</b>	
$R_{TMG} \geq \frac{V_{BAT} - 7.8 \text{ V}}{I_{\text{LOOP}}}$	$R_{TMG}$ is connected from $T_{MG}$ to $V_{BAT}$ and is used to limit power dissipation within the SLIC in Active and Disconnect states only.
$P_{RTMG} = \frac{(V_{BAT} - 7.8 \text{ V} - (I_L \cdot R_L))^2}{(R_{TMG} + 70 \Omega)^2} \cdot R_{TMG}$	Power dissipated in the thermal management resistor, $R_{TMG}$ , during Active and Disconnect states.
$P_{SLIC} = V_{BAT}(I_L) - P_{RTMG} - R_L(I_L)^2 + 0.12 \text{ W}$	Power dissipated in the SLIC while in Active and Disconnect states.

## DC FEED CHARACTERISTICS



$$R_{DC} = R_{DC1} + R_{DC2} = 31.25 \text{ k}\Omega$$

$$BAT = -48 \text{ V}$$

**Notes:**

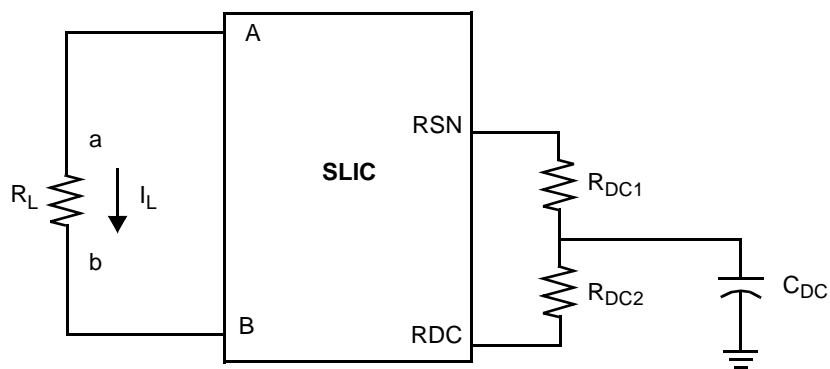
Curve is for illustration only.

$$1. \quad V_{AB} = I_L R_L' = \frac{1250}{R_{DC}} R_L' \quad \text{where } R_L' = R_L + 2R_F$$

$$2. \quad V_{AB} = |V_{BAT}| - 1.5 - I_L \left( \frac{R_{DC}}{113} \right)$$

$$3. \quad V_{AB} = |V_{BAT}| - 6.0 - I_L \left( \frac{R_{DC}}{113} \right)$$

### a. Load Line (Typical)

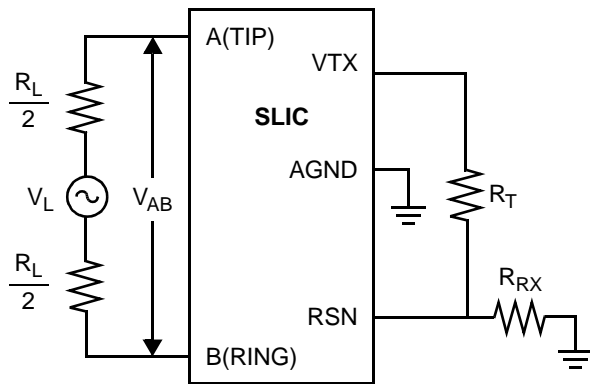


Feed current programmed by  $R_{DC1}$  and  $R_{DC2}$

### b. Feed Programming

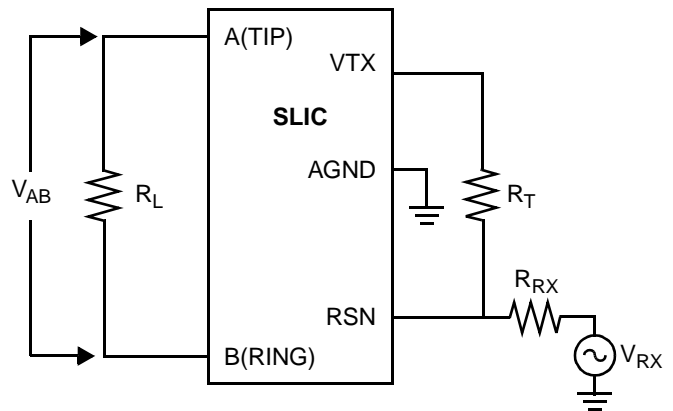
Figure 1. DC Feed Characteristics

## TEST CIRCUITS



$$I_{L2-4} = 20 \log (V_{TX} / V_{AB})$$

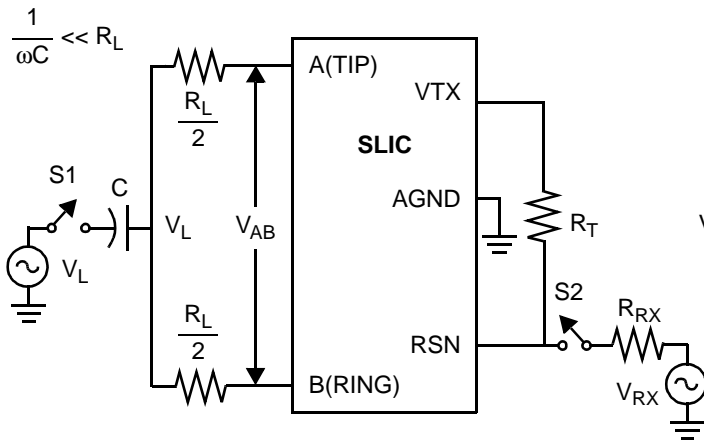
A. Two- to Four-Wire Insertion Loss



$$I_{L4-2} = 20 \log (V_{AB} / V_{RX})$$

$$BRS = 20 \log (V_{TX} / V_{RX})$$

B. Four- to Two-Wire Insertion Loss and Balance Return Signal



S2 Open, S1 Closed

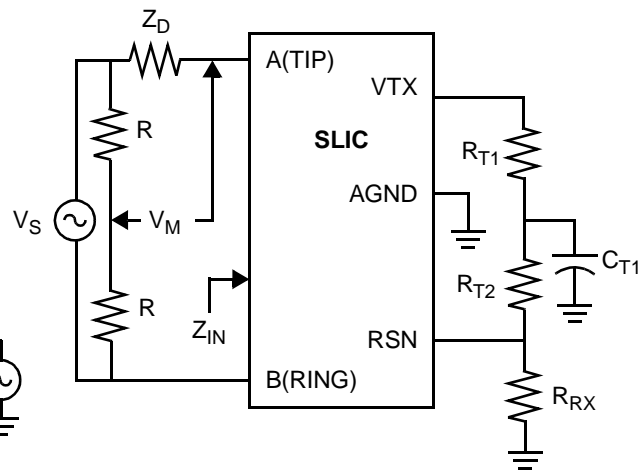
$$L-T \text{ Long. Bal.} = 20 \log (V_{AB} / V_L)$$

$$L-4 \text{ Long. Bal.} = 20 \log (V_{TX} / V_L)$$

S2 Closed, S1 Open

$$4-L \text{ Long. Sig. Gen.} = 20 \log (V_L / V_{RX})$$

C. Longitudinal Balance



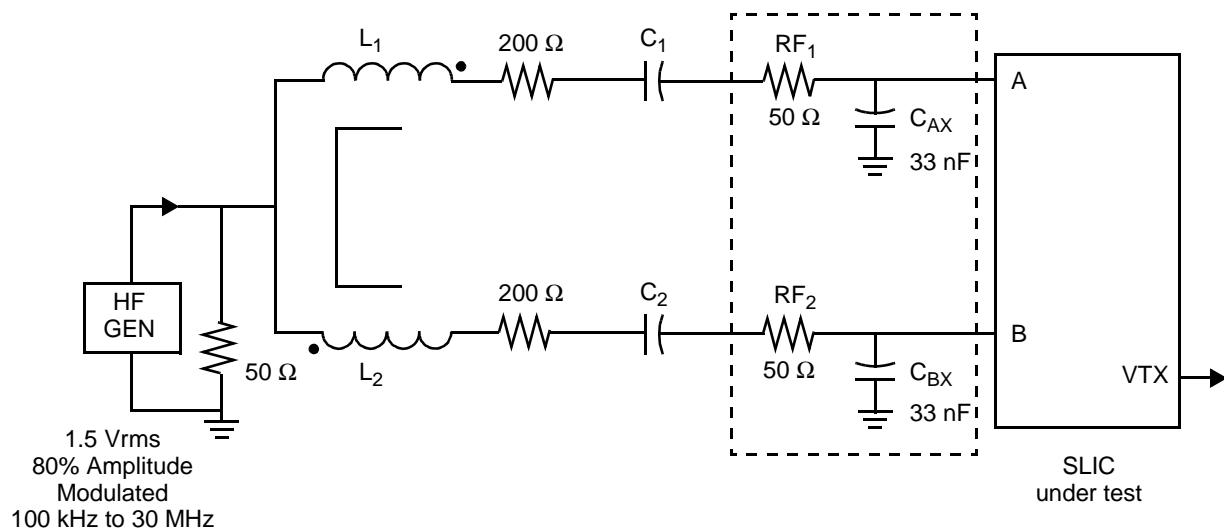
**Note:**

$Z_D$  is the desired impedance (e.g., the characteristic impedance of the line).

$$\text{Return Loss} = -20 \log (2 V_M / V_S)$$

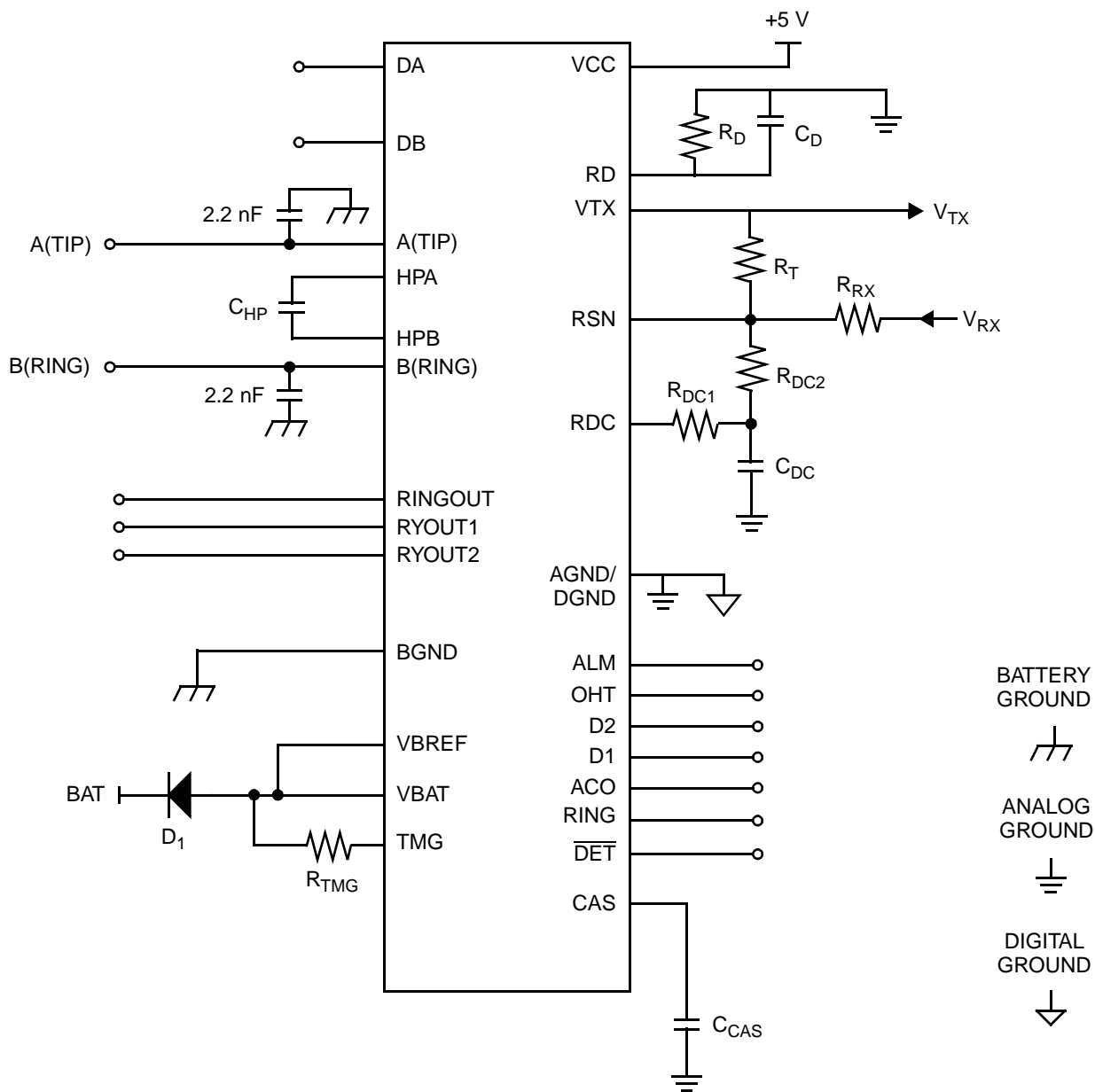
D. Two-Wire Return Loss Test Circuit

## TEST CIRCUITS (CONTINUED)

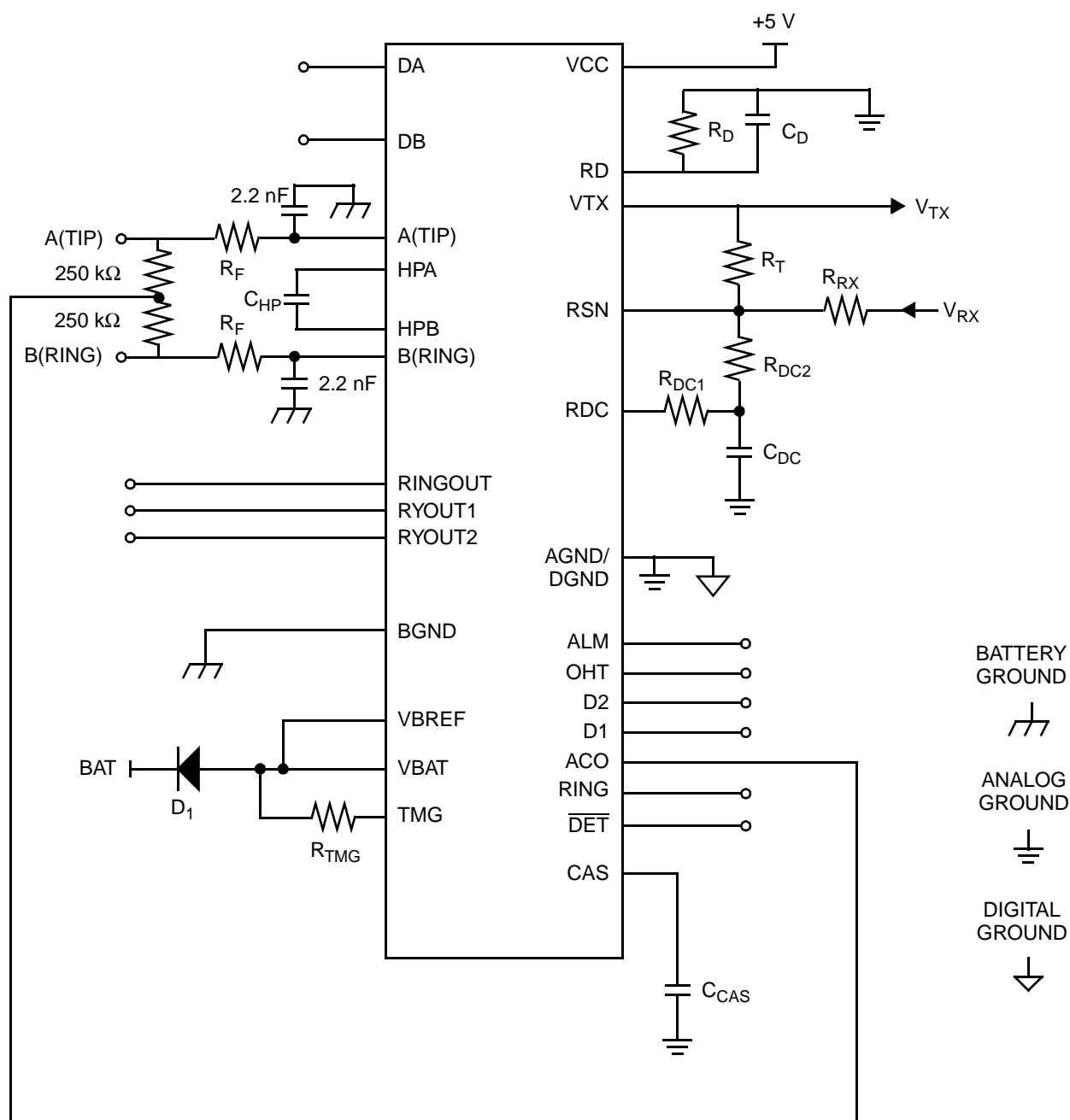


E. RFI Test Circuit

## TEST CIRCUITS (CONTINUED)



F. Am7924 Test Circuit



G. Am7924 Application Circuit

## REVISION SUMMARY

### Revision A to Revision B

- Under Operating Ranges, changed the VBAT value from  $-40.5$  V to  $-19$  V.
- Minor changes were made to the data sheet style and format to conform to AMD standards.

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